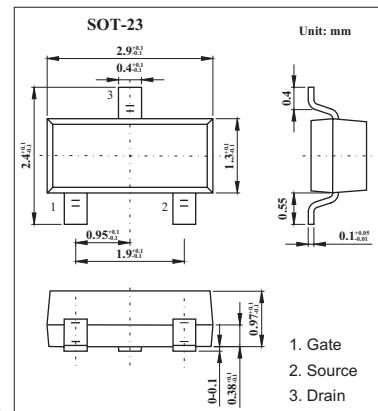
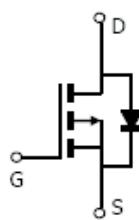


**P-Channel Enhancement Mode
Field Effect Transistor
KO3409(AO3409)**

■ Features

- V_{DS} (V) = -30V
- I_D = -2.6 A (V_{GS} = -10V)
- $R_{DS(ON)} < 130\text{m}\Omega$ (V_{GS} = -10V)
- $R_{DS(ON)} < 200\text{m}\Omega$ (V_{GS} = -4.5V)



■ Absolute Maximum Ratings $T_a = 25^\circ\text{C}$

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V_{DS}	-30	V
Gate-Source Voltage	V_{GS}	± 20	V
Continuous Drain Current $T_a=25^\circ\text{C}$	I_D	-2.6	A
		-2.2	
Pulsed Drain Current	I_{DM}	-20	
Power Dissipation $T_a=25^\circ\text{C}$	P_D	1.4	W
		1	
Thermal Resistance. Junction-to-Ambient	R_{thJA}	100	$^\circ\text{C}/\text{W}$
Thermal Resistance. Junction-to-Case	R_{thJC}	63	$^\circ\text{C}/\text{W}$
Junction and Storage Temperature Range	T_J, T_{STG}	-55 to 150	$^\circ\text{C}$

KO3409(AO3409)

■ Electrical Characteristics $T_a = 25^\circ\text{C}$

Parameter	Symbol	Testconditons	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	V_{DSS}	$I_D=250 \mu\text{A}, V_{GS}=0\text{V}$	-30			V
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS}=-24\text{V}, V_{GS}=0\text{V}$			-1	μA
		$V_{DS}=-24\text{V}, V_{GS}=0\text{V}, TJ=55^\circ\text{C}$			-5	
Gate-Body leakage current	I_{GSS}	$V_{DS}=0\text{V}, V_{GS}=\pm 20\text{V}$			± 100	nA
Gate Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS}=V_{GS}, I_D=-250 \mu\text{A}$	-1	-1.9	-3	V
Static Drain-Source On-Resistance	$r_{DS(\text{ON})}$	$V_{GS}=-10\text{V}, I_D=-2.6\text{A}$		97	130	$\text{m}\Omega$
		$V_{GS}=-10\text{V}, I_D=-2.6\text{A}, TJ=125^\circ\text{C}$		135	150	
		$V_{GS}=-4.5\text{V}, I_D=-2\text{A}$		166	200	
On state drain current	$I_{D(\text{ON})}$	$V_{GS}=-4.5\text{V}, V_{DS}=-5\text{V}$	-5			A
Forward Transconductance	g_{fs}	$V_{DS}=-5\text{V}, I_D=-5\text{A}$	3	3.8		S
Input Capacitance	C_{iss}	$V_{GS}=0\text{V}, V_{DS}=-15\text{V}, f=1\text{MHz}$		302	370	pF
Output Capacitance	C_{oss}			50.3		pF
Reverse Transfer Capacitance	C_{rss}			37.8		pF
Gate resistance	R_g	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		12	18	Ω
Total Gate Charge (10V)	Q_g	$V_{GS}=-4.5\text{V}, V_{DS}=-15\text{V}, I_D=-2.6\text{A}$		6.8	9	nC
Total Gate Charge (4.5V)				2.4		nC
Gate Source Charge	Q_{gs}	$V_{GS}=-10\text{V}, V_{DS}=-15\text{V}, R_L=5.8 \Omega, R_{GEN}=3 \Omega$		1.6		nC
Gate Drain Charge	Q_{gd}			0.95		nC
Turn-On DelayTime	$t_{D(\text{on})}$			7.5		ns
Turn-On Rise Time	t_r			3.2		ns
Turn-Off DelayTime	$t_{D(\text{off})}$			17		ns
Turn-Off Fall Time	t_f			6.8		ns
Body Diode Reverse Recovery Time	t_{rr}			16.8	22	ns
Body Diode Reverse Recovery Charge	Q_{rr}	$I_F=-2.6\text{A}, dI/dt=100\text{A}/\mu\text{s}$		10		nC
Maximum Body-Diode Continuous Current	I_s				-2	A
Diode Forward Voltage	V_{SD}	$I_s=-1\text{A}, V_{GS}=0\text{V}$		-0.82	-1	V

* Repetitive rating, pulse width limited by junction temperature.